

High Speed IGBT in Trench and Fieldstop Technology

Features:

- 1200V Trench + Field stop technology
- low switching losses
- positive temperature coefficient
- easy paralleling

Recommended for:

discrete components

Applications:

- high frequency drives
- UPS
- Welding
- Solar inverters



Chip Type	V _{CE}	<i>I</i> _{Cn}	Die Size	Package
IGC18T120T8Q	1200V	15A	4.16 x 4.34 mm ²	sawn on foil

Mechanical Parameters

Die size		4.16 x 4.34		
Emitter pad size		See chip drawing	mm^2	
Gate pad size		1.185 x 0.702		
Area total		18.1		
Thickness		115	μm	
Wafer size		200	mm	
Max.possible chips pe	er wafer	1510		
Passivation frontside		Photoimide		
Pad metal		3200 nm AlSiCu		
Backside metal		Ni Ag –system To achieve a reliable solder connection it is strongly recommended not to consume the Ni layer completely during production process		
Die bond		Electrically conductive epoxy glue and soft solder		
Wire bond		Al, <500μm		
Reject ink dot size		Ø 0.65mm ; max 1.2mm		
Storage environment	for original and sealed MBB bags	Ambient atmosphere air, Temperature 17°C – 2 < 6 month		
	for open MBB bags	Acc. to IEC62258-3: Atmosphere >99% Nitrogen or in Humidity <25%RH, Temperature 17°C – 25°C, < 6 r		



Maximum Ratings

Parameter	Symbol	Value	Unit
Collector-Emitter voltage, $T_{\rm vj}$ =25 °C	V _{CE}	1200	V
DC collector current, limited by $T_{\rm vj\;max}$	I _C	1)	Α
Pulsed collector current, t_p limited by $T_{vj \text{ max}}^{2}$	$I_{c,puls}$	45	Α
Gate emitter voltage	V _{GE}	±20	V
Operating junction temperature	T_{vj}	-40 +175	°C
Short circuit data $^{2 (3)}$ $V_{\text{GE}} = 15\text{V}$, $V_{\text{CC}} = 800\text{V}$, $T_{\text{vj}} = 150^{\circ}\text{C}$	tsc	10	μs

¹⁾ depending on thermal properties of assembly

Static Characteristics (tested on wafer), T_{vj} =25 °C

Parameter	Symbol	Conditions	Value			Unit
Tarameter	Cymbol	Conditions	min.	typ.	max.	
Collector-Emitter breakdown voltage	V _{(BR)CES}	$V_{\rm GE}$ =0V , $I_{\rm C}$ =0.5 mA	1200			
Collector-Emitter saturation voltage	V _{CEsat}	V _{GE} =15V, I _C =15A	1.78	2.05	2.42	V
Gate-Emitter threshold voltage	$V_{\rm GE(th)}$	$I_{\rm C}$ =0.5mA , $V_{\rm GE}$ = $V_{\rm CE}$	5.3	5.8	6.3	
Zero gate voltage collector current	I _{CES}	V _{CE} =1200V , V _{GE} =0V			2	μA
Gate-Emitter leakage current	I _{GES}	V_{CE} =0V , V_{GE} =20V			120	nA
Integrated gate resistor	$r_{\rm G}$			none		Ω

Electrical Characteristics (not subject to production test - verified by design / characterization)

Parameter	Symbol	Conditions	Value			l lm:4
Parameter		Conditions	min.	typ.	max.	Unit
Collector-Emitter saturation voltage	V _{CEsat}	$V_{\rm GE}$ =15V, $I_{\rm C}$ =15A, $T_{\rm vj}$ =175 °C		2.7		V
Input capacitance	C _{ies}	$V_{CE}=25V$, $V_{GE}=0V$, $f=1MHz$		875		pF
Reverse transfer capacitance	C_{res}	$T_{\rm vj}$ =25 °C		45		

²⁾ not subject to production test - verified by design/characterization

³⁾ allowed number of short circuits: <1000; time between short circuits: >1s.



Further Electrical Characteristic

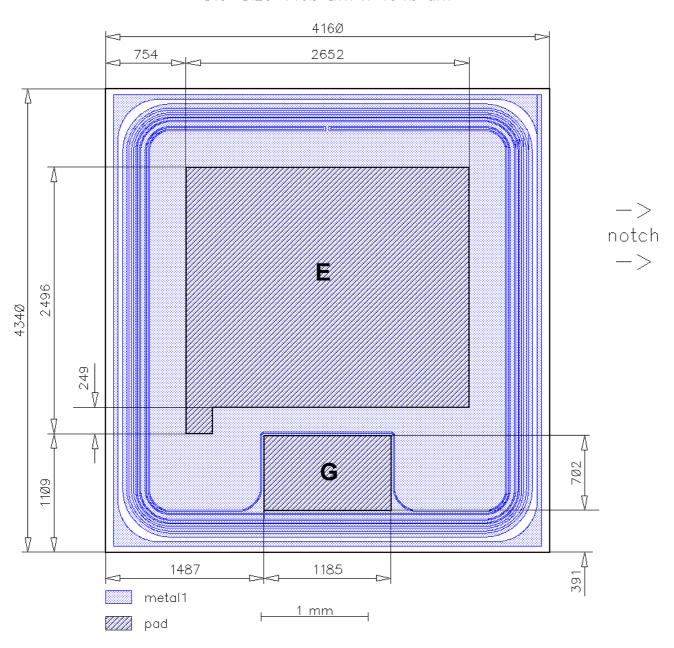
Switching characteristics and thermal properties are depending strongly on module design and mounting technology and can therefore not be specified for a bare die.

This chip data sheet refers to the device data sheet	IKW15N120H3	Rev 1.2
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Chip Drawing

Die-Size 4160 um x 4340 um



E = Emitter

G = Gate



Description
AQL 0,65 for visual inspection according to failure catalogue
Electrostatic Discharge Sensitive Device according to MIL-STD 883

Revision History

Version	Subjects (major changes since last revision)	Date

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